



Condition Monitoring and Their Applications in Industry

Guest Editors:

Prof. Dr. Tat-Hean Gan

Brunel University London,
Uxbridge, United Kingdom

Prof. Dr. David Mba

Executive Office, University of the
Arts London, 272 High Holborn,
London WC1V 7EY, UK

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Message from the Guest Editors

Dear Colleagues,

Critical assets such as machinery and structures are essential for economic activities across most sectors. Condition monitoring of these critical assets is essential for optimal usage. Such monitoring processes involve detecting faults at an early stage, diagnosing the fault source and monitoring and predicting the fault progression. Achieving these objectives successfully for both machinery and structures requires use of a range of data analysis techniques that are typically developed for the specific application. While numerous theoretical data analysis, machine learning and signal processing techniques have evolved, this Special Edition presents only industrial-application-based papers in which the latest condition monitoring techniques are applied to machinery and structures.

Keywords:

- Condition monitoring
- Machinery
- Structures
- Diagnosis
- Prognosis





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Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo
Dipartimento di Fisica,
Politecnico di Milano, Piazza L.
da Vinci 32, 20133 Milano, Italy

Message from the Editor-in-Chief

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Applied Sciences Editorial Office
MDPI, Grosspeteranlage 5
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